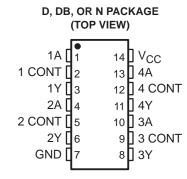
SN75C189, SN75C189A QUADRUPLE LOW-POWER LINE RECEIVERS

SLLS041G - OCTOBER 1988 - REVISED JANUARY 2000

- Meet or Exceed the Requirements of TIA/EIA-232-F and ITU Recommendation V.28
- Low Supply Current . . . 420 μA Typ
- Preset On-Chip Input Noise Filter
- Built-in Input Hysteresis
- Response and Threshold Control Inputs
- Push-Pull Outputs
- Functionally Interchangeable and Pin-to-Pin Compatible With Texas Instruments SN75189/SN75189A and Motorola MC1489/MC1489A
- Package Options Include Plastic Small-Outline (D) and Shrink Small-Outline (DB) Packages, and Standard Plastic (N) DIP



description

The SN75C189 and SN75C189A are low-power, bipolar, quadruple line receivers that are used to interface data terminal equipment (DTE) with data circuit-terminating equipment (DCE). These devices have been designed to conform to TIA/EIA-232-F.

The SN75C189 has a 0.33-V typical hysteresis, compared with 0.97 V for the SN75C189A. Each receiver has provision for adjustment of the overall input threshold levels. This is achieved by choosing external series resistors and voltages to provide bias levels for the response-control pins. The output is in the high logic state if the input is open circuit or shorted to ground.

These devices have an on-chip filter that rejects input pulses of less than 1-µs duration. An external capacitor can be connected from the control pins to ground to provide further input noise filtering for each receiver.

The SN75C189 and SN75C189A have been designed using low-power techniques in a bipolar technology. In most applications, these receivers interface to single inputs of peripheral devices such as UARTs, ACEs, or microprocessors. By using sampling, such peripheral devices usually are insensitive to the transition times of the input signals. If this is not the case, or for other uses, it is recommended that the SN75C189 and SN75C189A outputs be buffered by single Schmitt input gates or single gates of the HCMOS, ALS, or 74F logic families.

The SN75C189 and SN75C189A are characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

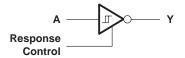


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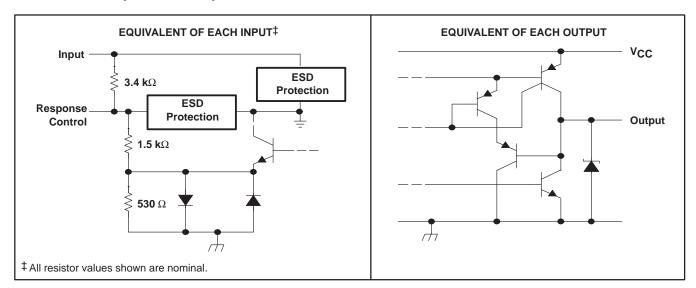
logic symbol†

╜ **THRESHOLD** 1 CONT **ADJUST** 4 6 2 CONT 10 **3A** 3 CONT 13 12 4 CONT

logic diagram (each receiver)



schematic of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage, V _{CC} (see Note 1)		
Input voltage range, V ₁		
Output voltage range, VO		0.3 V to V _{CC} + 0.3 V
Package thermal impedance, θ _{JA} (see Note 2	:): D package	86°C/W
	DB package	96°C/W
	N package	
Lead temperature 1,6 mm (1/16 inch) from cas	se for 10 seconds	260°C
Storage temperature range, T _{stg}		–65°C to 150°C

[§] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to network GND.

2. The package thermal impedance is calculated in accordance with JESD 51.



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	6	V
VI	Input voltage (see Note 3)	-25		25	V
IOH	High-level output current			-3.2	mA
loL	Low-level output current			3.2	mA
	Response-control current			±1	mA
TA	Operating free-air temperature	0		70	°C

NOTE 3: The algebraic convention, where the more positive (less negative) limit is designated as maximum, is used in this data sheet for logic levels only, e.g., if –10 V is a maximum, the typical value is a more negative voltage.

electrical characteristics over recommended free-air temperature range, V_{CC} = 5 V \pm 10% (unless otherwise noted) (see Note 4)

PARAMETER			TEST COND	MIN	TYP [†]	MAX	UNIT	
\/-	Positive going input threshold veltage	'C189	See Figure 1		1		1.5	V
VIT+	Positive-going input threshold voltage	'C189A			1.6		2.25	
\/	Via Negative going input threshold voltage (C189)		0.75	0.75	1.25	V		
VIT-	Negative-going input threshold voltage	'C189A	See Figure 1		0.75	1	1.25	V
Vi lanut buat	Input hystoresis voltage (Viz. – Viz.)	'C189	See Figure 1		0.15	0.33		V
Vhys	Input hysteresis voltage (V _{IT+} – V _{IT-})	'C189A	See Figure 1		0.65	0.97		ı v
V _{OH} High-level output voltage		$V_{CC} = 4.5 \text{ V to 6 V},$ $I_{OH} = -20 \mu\text{A}$	$V_{I} = 0.75 V$,	3.5			V	
		$V_{CC} = 4.5 \text{ V to 6 V},$ $I_{OH} = -3.2 \text{ mA}$	V _I = 0.75 V,	2.5			V	
V _{OL} Low-level output voltage		$V_{CC} = 4.5 \text{ V to 6 V},$ $I_{OL} = 3.2 \text{ mA}$	V _I = 3 V,			0.4	>	
I	L. High level input suggest	Soo Figur	See Figure 2 $V_I = 25 V_I$	V _I = 25 V	3.6		8.3	mA
l IIH	High-level input current		See Figure 2	V _I = 3 V	0.43		1	IIIA
I _{IL} Low-level input current	Low level input ourrent	V _I = −25 V	V _I = -25 V	-3.6		-8.3	mA	
	Low-level input current		See Figure 2	V _I = -3 V	-0.43		-1	IIIA
IOS Short-circuit output current		See Figure 3				-35	mA	
Icc	Ico Supply current		V _I = 5 V, See Figure 2	No load,		420	700	μА

[†] All typical values are at $T_A = 25$ °C.

NOTE 4: All characteristics are measured with response-control terminal open.

switching characteristics, V_{CC} = 5 V $\pm 10\%$, T_A = 25°C

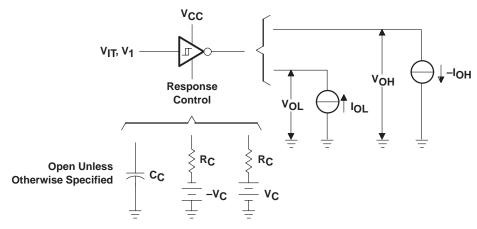
PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
tPLH	Propagation delay time, low- to high-level output						6	μs
tPHL	Propagation delay time, high- to low-level output						6	μs
tTLH	Transition time, low- to high-level output‡	$R_L = 5 k\Omega$,	$C_{L} = 50 pF$,	See Figure 4			500	ns
tTHL	Transition time, high- to low-level output‡						300	ns
t _{w(N)}	Duration of longest pulse rejected as noise§				1		6	μs

[‡] Measured between 10% and 90% points of output waveform



[§] The receiver ignores any positive- or negative-going pulse that is less than the minimum value of $t_{W(N)}$ and accepts any positive- or negative-going pulse greater than the maximum of $t_{W(N)}$.

PARAMETER MEASUREMENT INFORMATION

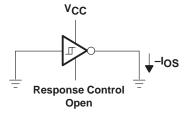


NOTE A: Arrows indicate actual direction of current flow. Current into a terminal is a positive value.

Figure 1. V_{T+} , V_{IT-} , V_{OH} , V_{OL}

NOTE A: Arrows indicate actual direction of current flow. Current into a terminal is a positive value.

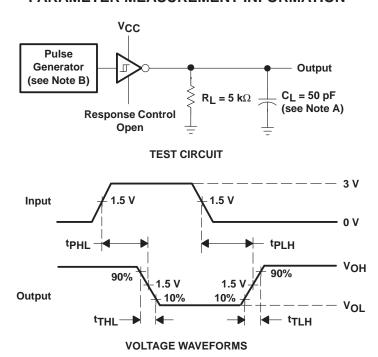
Figure 2. I_{IH}, I_{IL}, I_{CC}



NOTE A: Arrows indicate actual direction of current flow. Current into a terminal is a positive value.

Figure 3. Ios

PARAMETER MEASUREMENT INFORMATION

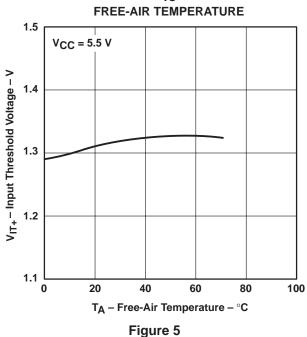


NOTES: A. C_L includes probe and jig capacitances.

B. The pulse generator has the following characteristics: Z $_{O}$ = 50 $\Omega,\,t_{W}$ = 25 $\mu s.$

Figure 4. Test Circuit and Voltage Waveforms

SN75C189 INPUT THRESHOLD VOLTAGE (POSITIVE GOING) vs



SN75C189A INPUT THRESHOLD VOLTAGE (POSITIVE GOING)

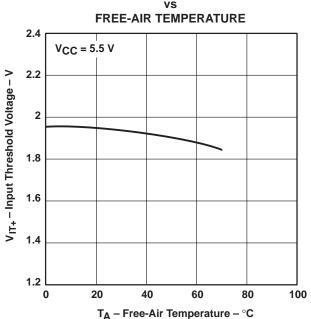
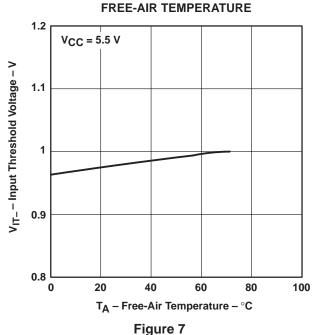
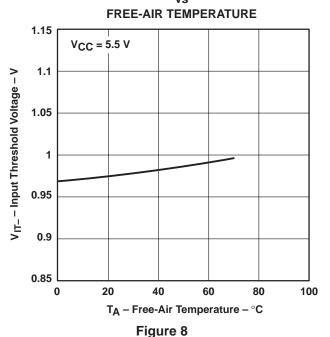


Figure 6

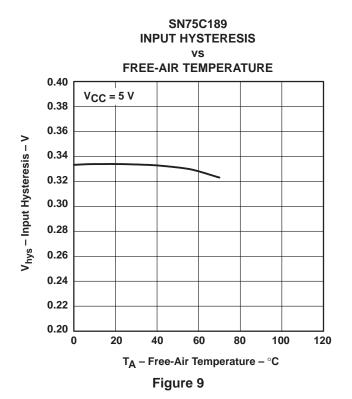
SN75C189 INPUT THRESHOLD VOLTAGE (NEGATIVE GOING) vs

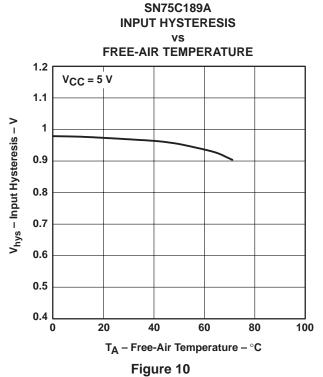


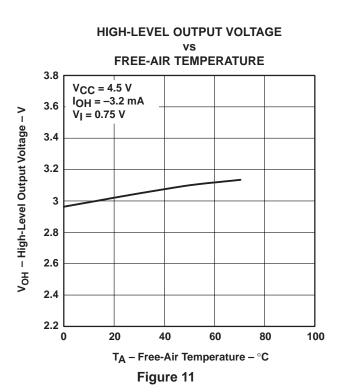
SN75C189A INPUT THRESHOLD VOLTAGE (NEGATIVE GOING) vs

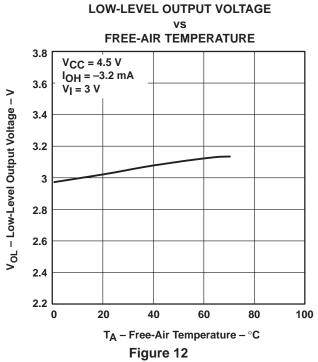


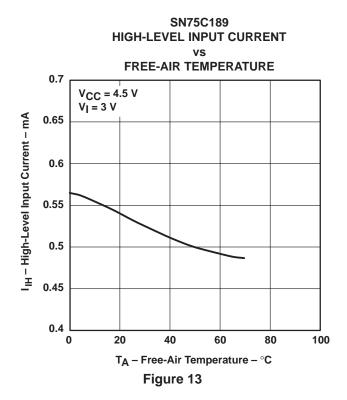


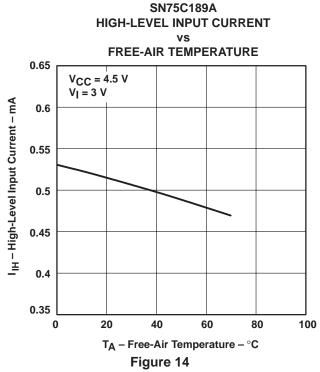


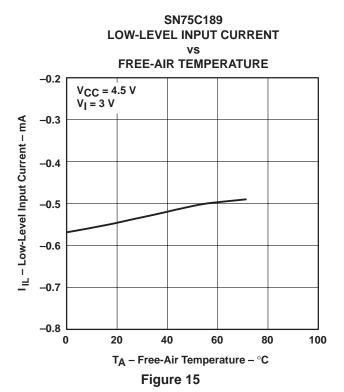


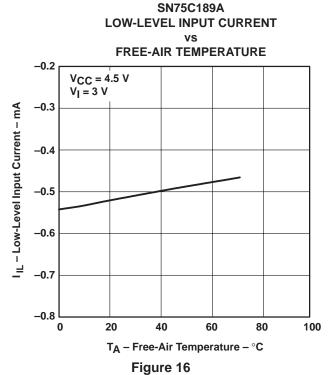












HIGH-LEVEL SHORT-CIRCUIT OUTPUT CURRENT

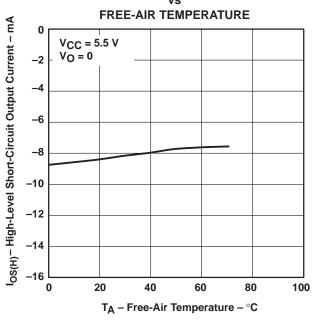


Figure 17

LOW-LEVEL SHORT-CIRCUIT OUTPUT CURRENT

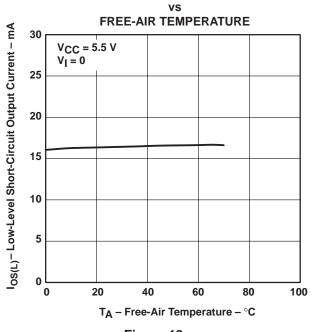


Figure 18

SUPPLY CURRENT vs

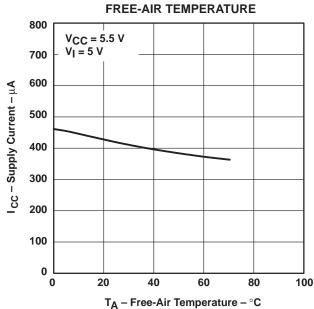


Figure 19

PROPAGATION DELAY TIME,

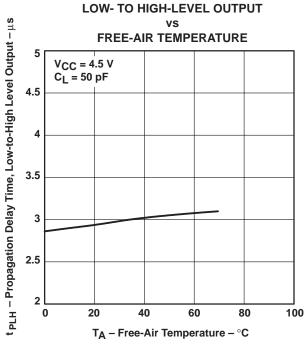
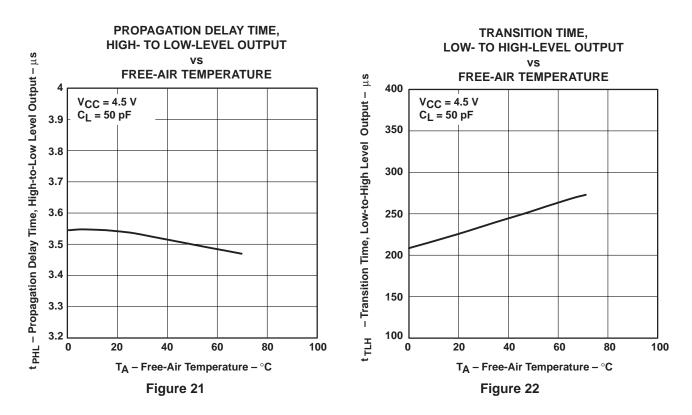


Figure 20



TRANSITION TIME, HIGH- TO LOW-LEVEL OUTPUT

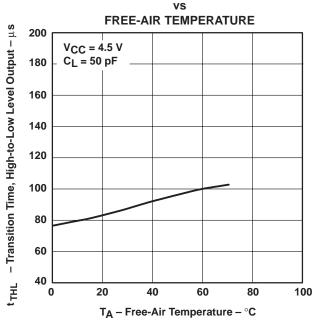


Figure 23

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